EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	9656	((semiconductor chip circuit electronic) near3 (sort$3 separat$3 process$3 test$3)) same ((test result flag) and reliability)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/06 14:45
L3	2417	((semiconductor chip circuit electronic) near3 (sort$3 separat$3 process$3 test$3)) same ((test result flag) near3 reliability)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/06 14:47
L4	14349	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/01/06 14:46
L5	251	l3 and l4	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/06 14:46
L6	519	((semiconductor chip circuit electronic) near3 (sort$3 separat$3 process$3 test$3)) same (different and (test result flag) near3 reliability)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/06 14:47
L7	96	l4 and l6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/06 14:47